

# Allowed number of bunches for ADT coherent excitation during Run III and for HL-LHC

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## **ADT** coherent excitation

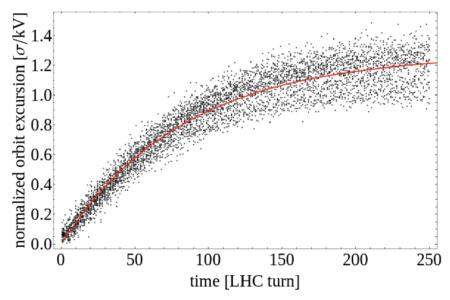
#### **ADT** operation in coherent excitation mode

- Potential fast-failure leading to beam losses reaching the critical loss limit within few milliseconds
- Orbit excursion is a superposition of coherent excitation and always-on damping (see figure)

#### **Objectives**

- Provides estimates on the time-dynamics of beam losses for various ADT operation modes
- Determine the operational envelope for allowed operation with the ADT in coherent excitation during Run III and for HL-LHC, in terms of
  - Length of the excitation window (number of bunches)
  - Maximum allowed voltage

#### **ADT** model from measurements



**Measured coherent excitation** of the beam by the ADT normalized to the applied voltage at 6.5 TeV with fitted scaling law

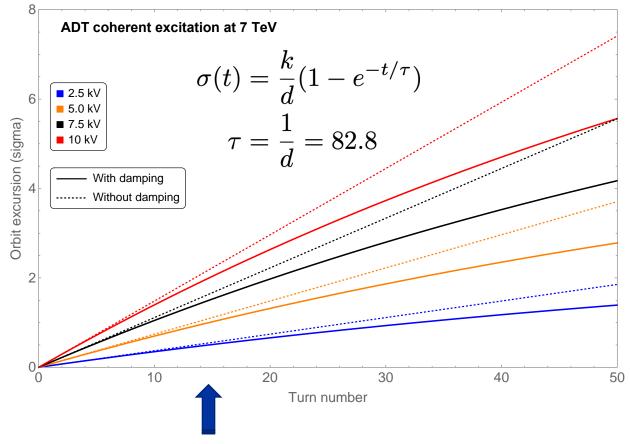
$$\frac{d}{dt}\sigma(t) = k - d \cdot \sigma(t)$$
$$\sigma(t) = \frac{k}{d} \left(1 - e^{-d \cdot t}\right)$$

B. Lindstrom, et al., Phys. Rev. Accel. Beams 23, 081001

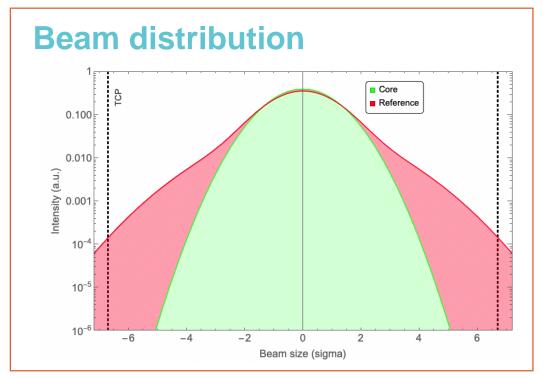


## **Parametric models**

#### **ADT** excitation



Critical orbit excursion reached around turn 14 for a full machine



|                 | LHC Run III                        | HL-LHC                |
|-----------------|------------------------------------|-----------------------|
| Beam energy     | 450 GeV and 7 TeV                  |                       |
| Bunch intensity | 1.8 e11 protons/bunch              | 2.2 e11 protons/bunch |
| TCP settings    | 6.5 sigma*                         | 6.7 sigma             |
| BCCM threshold  | 6e11 @ 450 GeV and 3e11 @ 7 TeV ** |                       |

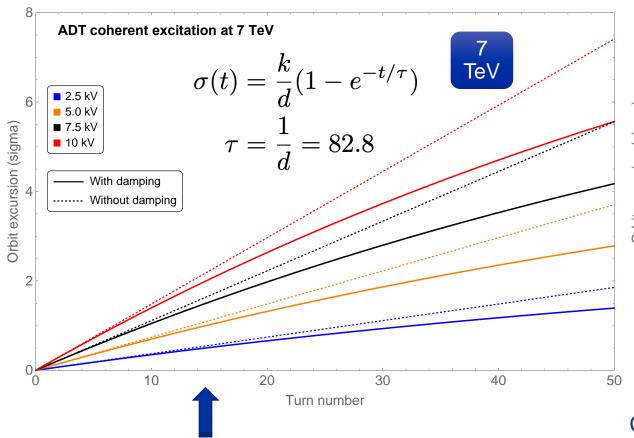
<sup>\* 5.5</sup> sigma scaled from 3.5  $\mu$ m down to 2.5  $\mu$ m



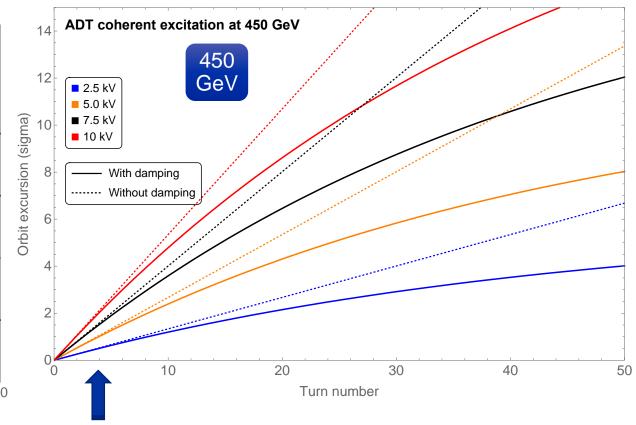
<sup>\*\*</sup> for short windows (≤ 64 turns)

## **Parametric models**

#### **ADT** excitation



Critical orbit excursion reached around turn 14 for a full machine



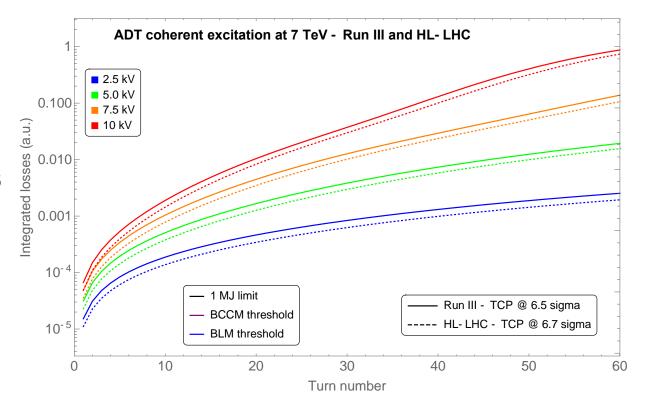
Critical orbit excursion reached around turn 4 for a full machine

Much faster excitation at 450 GeV!



## Integrated beam losses

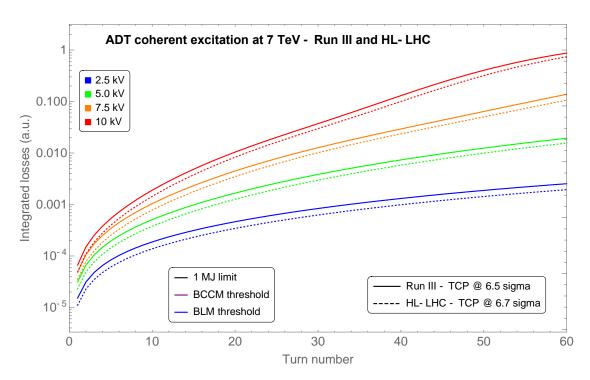
- Semi-analytical model to compute the losses: integration over the beam distribution
- 1 MJ of beam losses used as baseline critical loss limit assumed for machine protection
- BLM detection with operational threshold for RS01-06 at 125kJ (assumed in IR7 over a few milliseconds)
- BCCM threshold at 3e11 protons for 1-turn window
- Key considerations
  - Failure detection is indirect: BLMs and BCCM.
  - The failure onset is not observable. Failure onset to damage limit margin is less relevant for indirectly detected failures.
  - Need to consider the margin between failure detection and critical loss limit.
  - Need to consider injection and top energy as much more strength available at 450 GeV



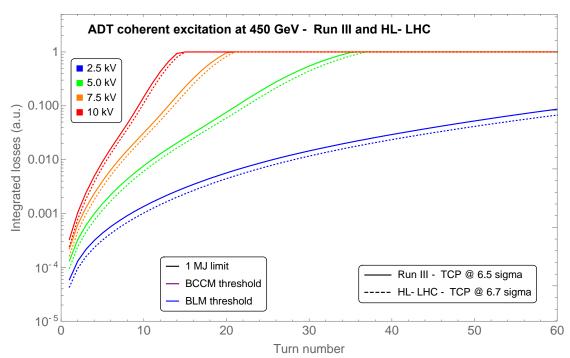
- Integrated fractional beam losses as a function of the turn number for different ADT voltages.
- > BCCM and BLM thresholds shown for a full machine (2748 bunches).



## Integrated beam losses



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- > BCCM and BLM thresholds shown for a full machine (2748 bunches).



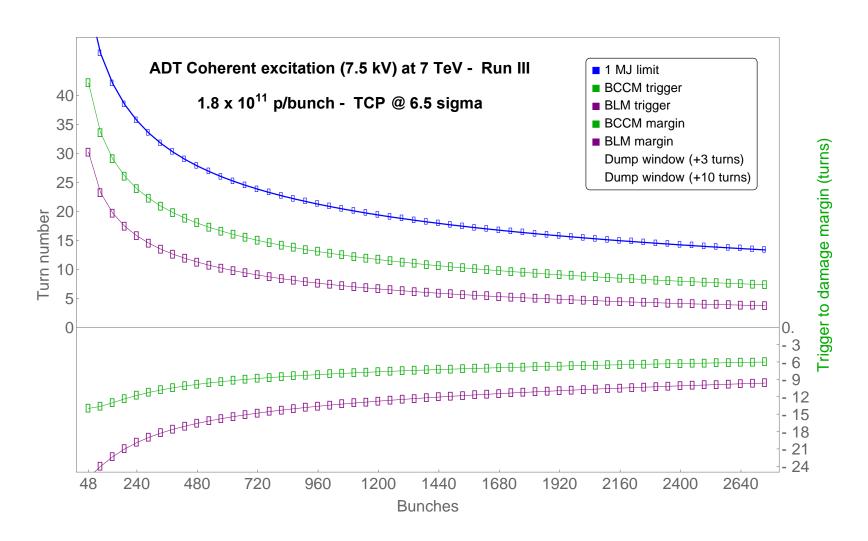
#### Key considerations

- Failure detection is indirect: BLMs and BCCM.
- The failure onset is not observable. Failure onset to damage limit margin is less relevant for indirectly detected failures.
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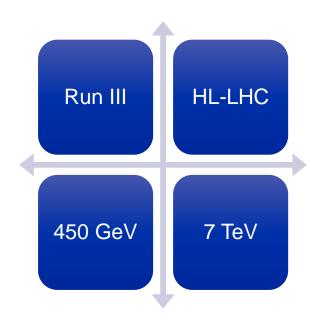
## Losses and margins – Run III – 7.5 kV

- 1. For a given number of bunches, compute
  - The 1MJ critical loss limit
  - The BCCM loss limit
  - The BLM loss limit
- 2. With the loss limits, inverse the loss v. time relationship (see previous slide/figure)
- 3. Obtain the turn number at which the event occurs
- 4. Compute the trigger to damage margin





## Results and proposals



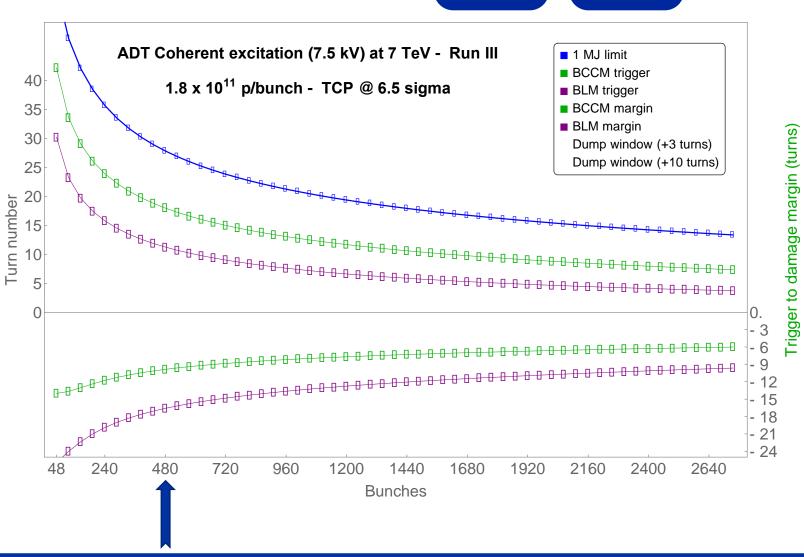


## Losses and margins – 7.5 kV

Run III 7 TeV

Conservative 10 turn margin even for the BCCM trigger with up to 2 full batches

2 batches (480 bunches) proposed as maximum allowed number of bunches





## Losses and margins – 10.0 kV

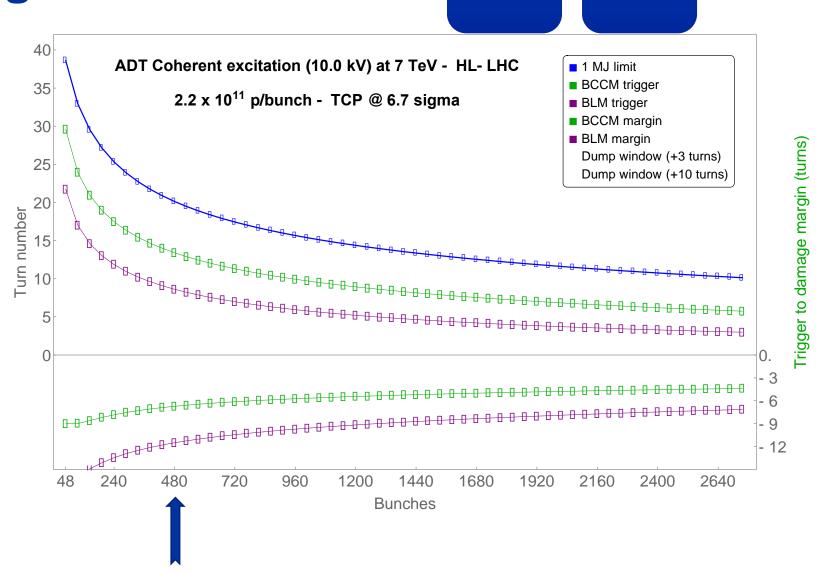
HL-LHC

7 TeV

Margin w.r.t BCCM threshold always below 10 turns

2 batches still provide sufficient margin w.r.t BLM threshold and acceptable limit w.r.t BCCM threshold (7 turns)

2 batches (480 bunches) proposed as maximum allowed number of bunches





## Losses and margins – 7.5 kV

Run III

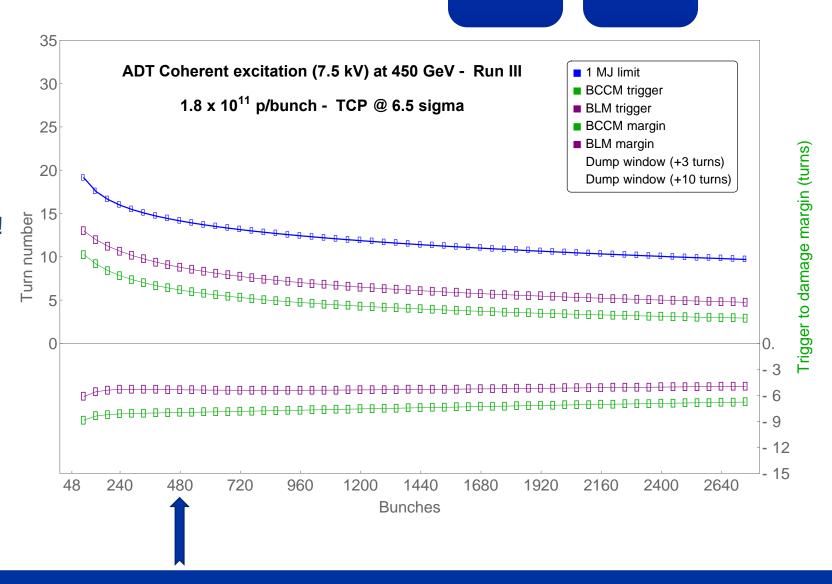
450 GeV

BLMs do not trigger first (BCCM is the first trigger)

#### Limited margin with the BLMs...

... but relatively flat curve as a function of the number of bunches!

2 batches (480 bunches) provide a 5 turn margin (BLMs) and 8 turn margin (BCCM)





## Losses and margins – 10.0 kV

**HL-LHC** 

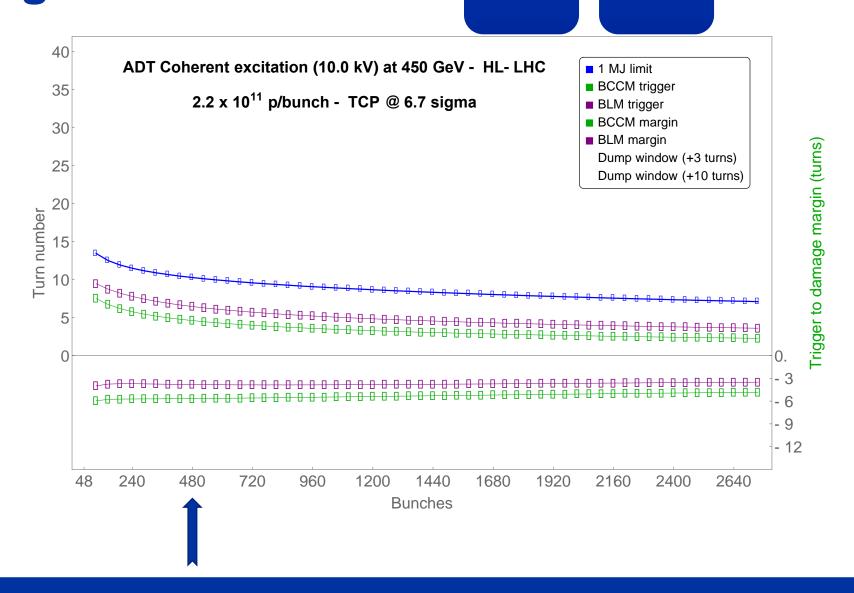
450 GeV

BLMs do not trigger first (BCCM is the first trigger)

Very limited margin with the BLMs...

Need to reduce the voltage?

2 batches (480 bunches) provide a 4 turn margin (BLMs) and 6 turn margin (BCCM)





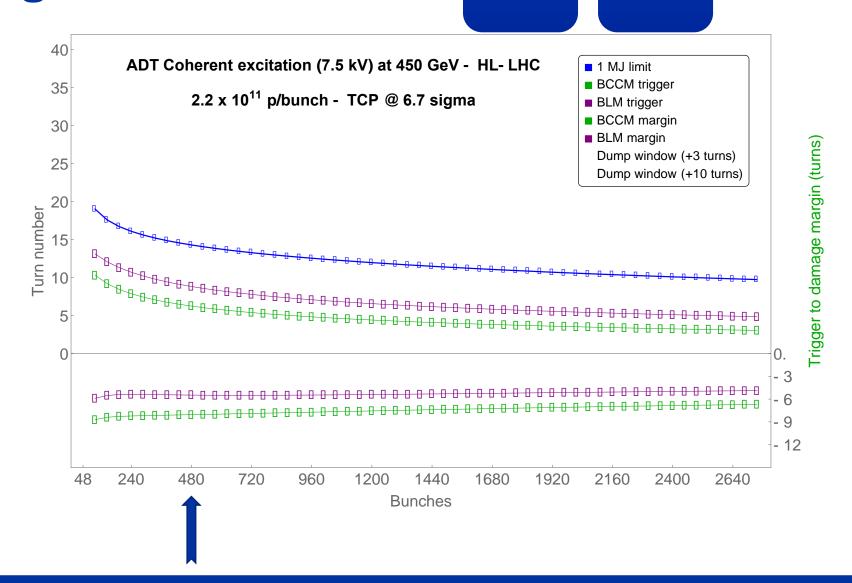
## Losses and margins – 7.5 kV

**HL-LHC** 

450 GeV

Reducing the voltage to 7.5 kV restores acceptable margins.

2 batches (480 bunches) provide a 5 turn margin (BLMs) and 8 turn margin (BCCM)





## Losses and margins – 5.0 kV

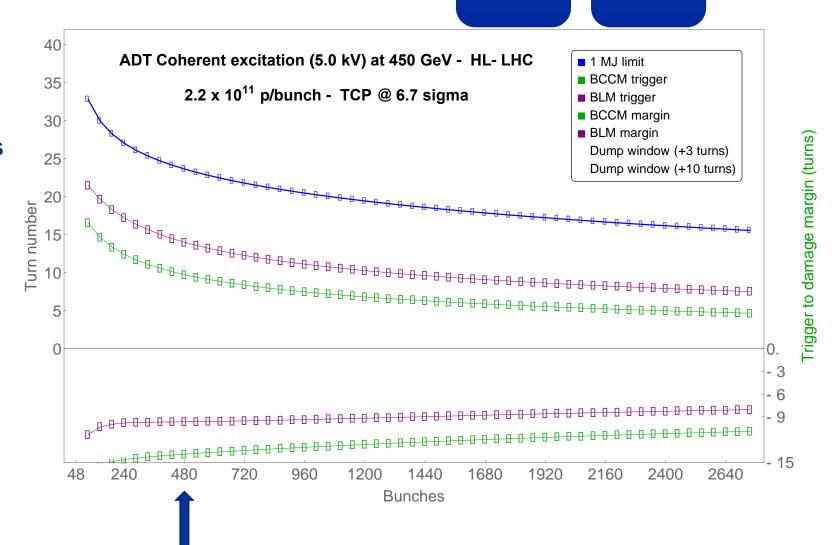
**HL-LHC** 

450 GeV

Further reducing the voltage to 5.0kV restores a 10-turn margin for 2 batches (similar margin as for top energy)

Note that the BCCM still triggers first

2 batches (480 bunches) provide a 10-turn margin (BLMs) and 15-turn margin (BCCM)





## **Conclusions and proposals**

#### Conclusions

- Estimates provided for LHC Run 3 and HL-LHC for the margin between the failure trigger (BLM or BCCM thresholds) and the damage limit machine protection threshold
- Maximum voltage (10.0 kV) is not an issue at 7 TeV but needs to be limited at 450 GeV

#### Proposal

- Limit the ADT window length to 2 batches (480 bunches) for Run 3 and for HL-LHC
- ADT window length: 14.4 μs or bunch by bunch
- Limit maximum voltage (for beam excitation) at injection energy
- Provides flexible use of the ADT during operation and MD's while preserving sufficient margin

#### **Baseline filling scheme**

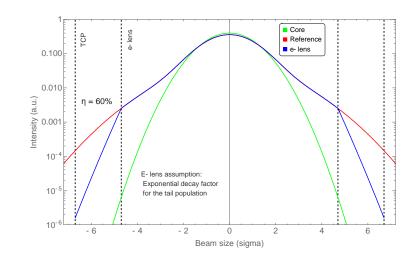
#### BCMS

- 5x48b/inj, SPS batch spacing 200ns and LHC batch spacing 800ns
- 240b/inj, train length of 6.8 μs



## A few more things...





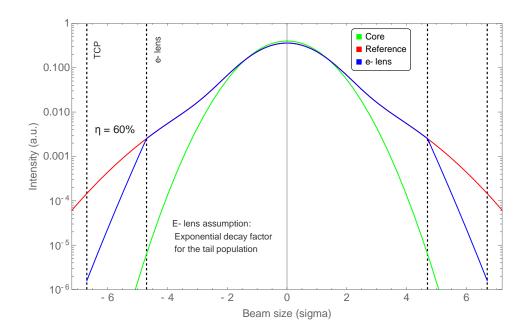
## Depleted transverse halo

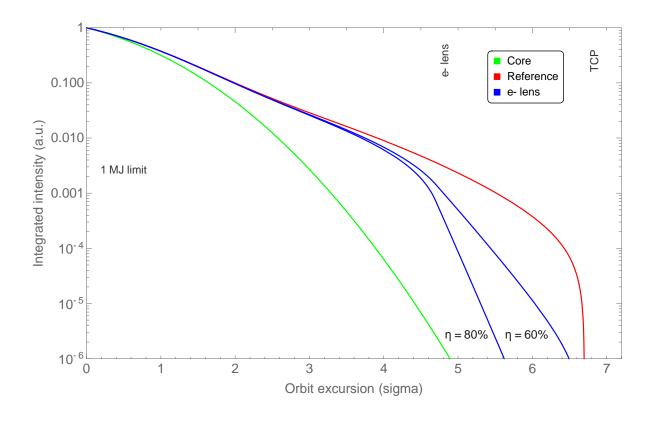
Considerations for the hollow electron-lens



## Integrated beam losses with e-lens

- Transverse distribution with depleted beam halo
- A given integrated loss level happen at a later turn with increasing depletion level



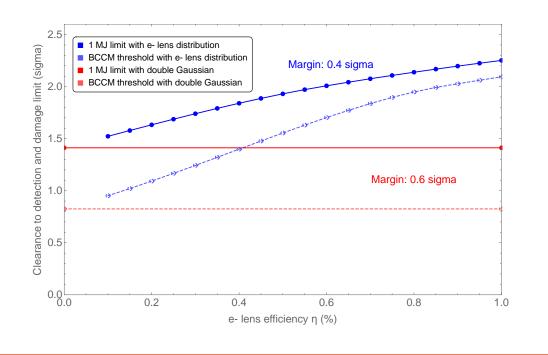


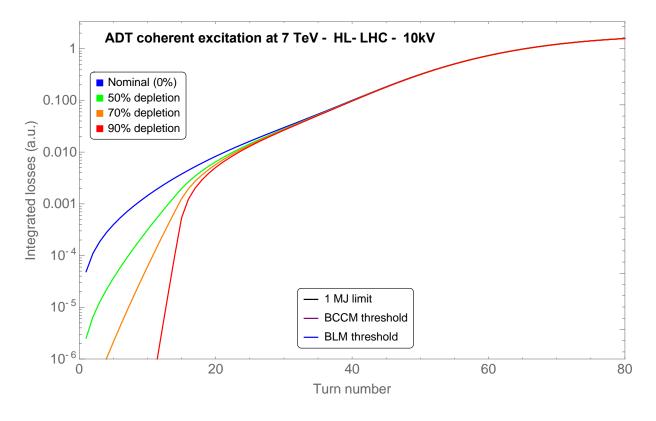
- > Integrated fractional beam losses as a function of orbit excursion.
- ➤ Larger orbit excursions can be tolerated at the price of increased steepness of the integrated losses curve



## Integrated beam losses with e-lens

## Margins between given thresholds (BCCM or BLM) and damage limit are reduced with increased halo depletion

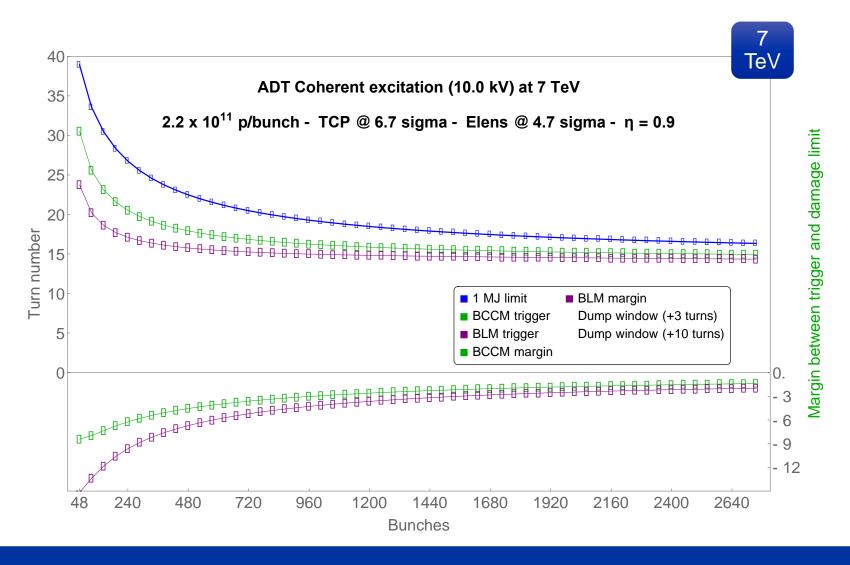




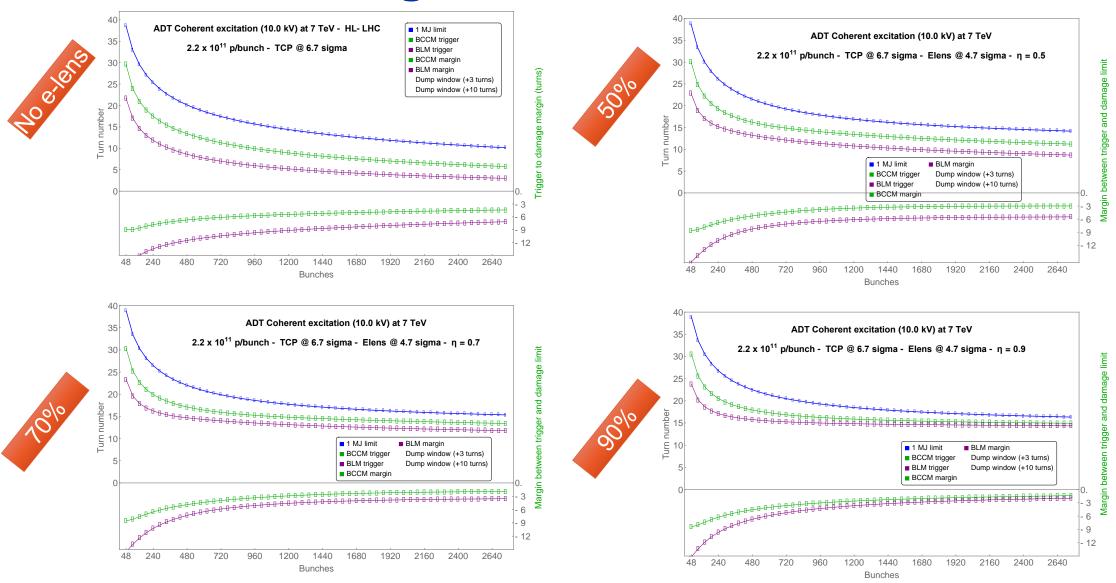
- ➤ Integrated fractional beam losses as a function of the turn number for different halo depletion.
- > BCCM and BLM thresholds shown for a full machine (2748 bunches).



 For 90% depletion 1 batch can still be considered safe with enough margin



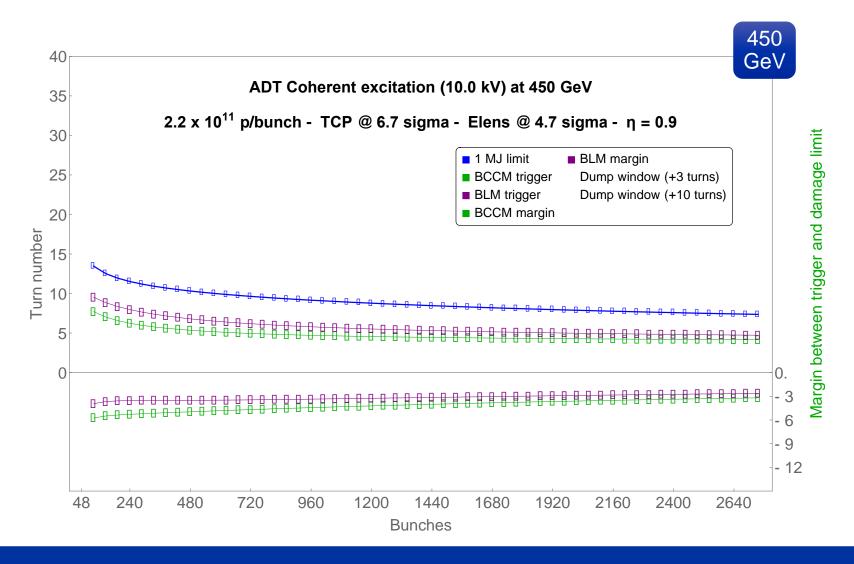




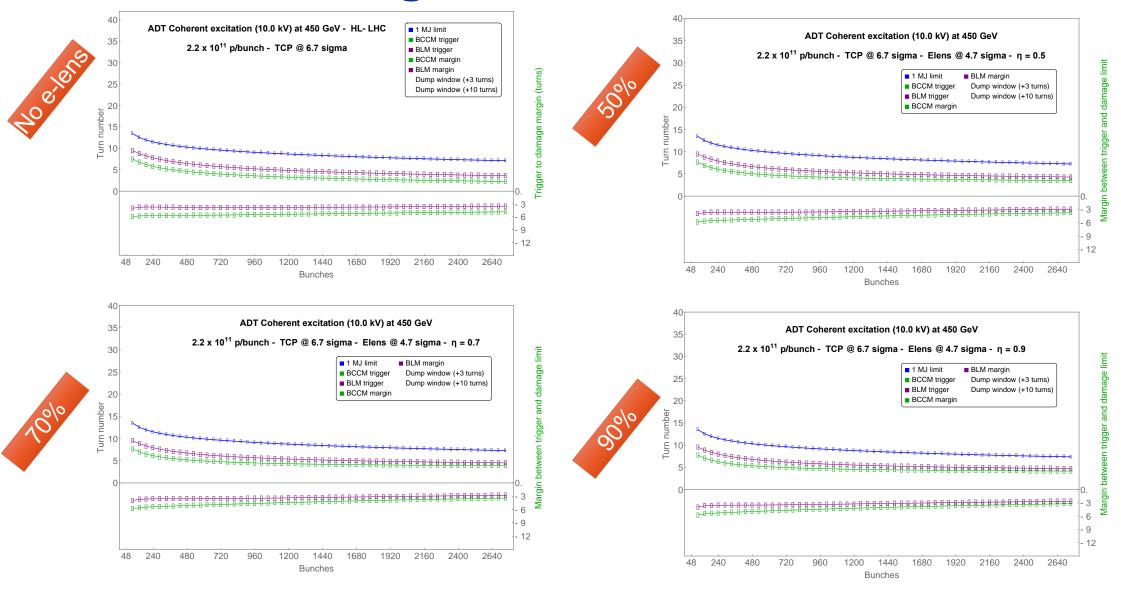




- Extremely limited margin even for a single batch
- Losses are high even for a non-depleted distribution



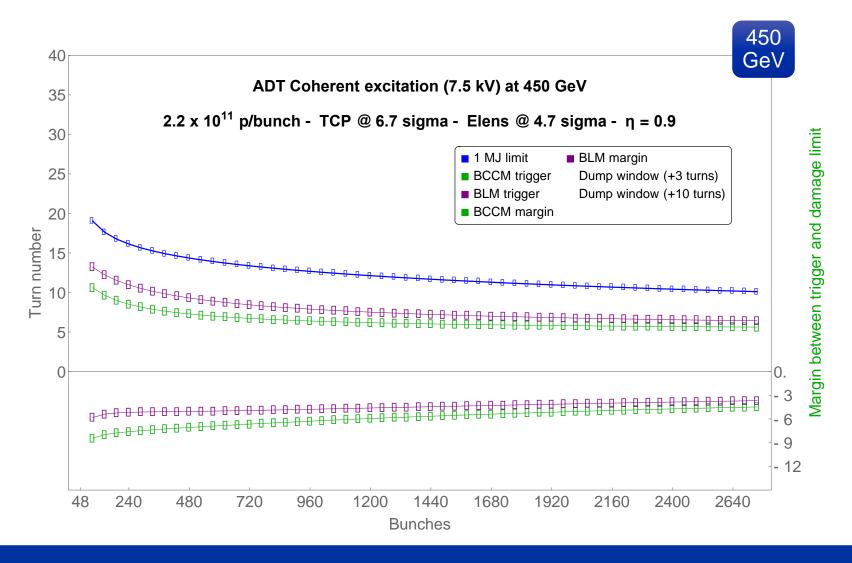




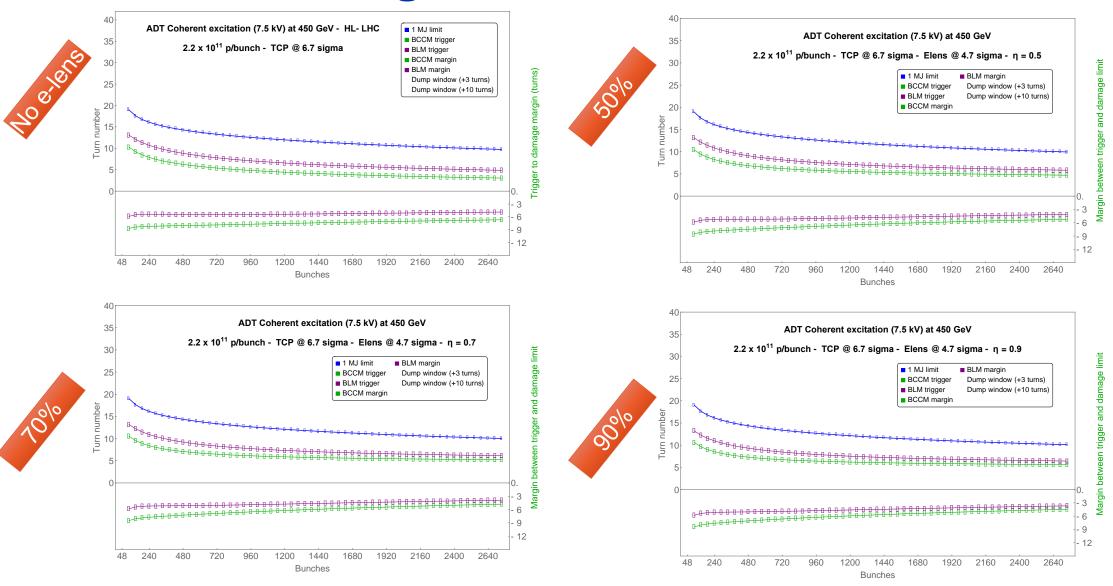




- Reducing the voltage to 7.5 kV restores enough margin for 1 batch
- Due to the very fast losses, the e-lens efficiency (halo depletion factor) does not affect the results strongly











## Proposal for depleted transverse halo

#### Proposal

- Limit the ADT window length to 1 batches (240 bunches) for HL-LHC with HEL operation
- ADT window length: 6.8 μs
- Limit maximum voltage at injection energy
- Similar margin as for Run 3 and HL-LHC without HEL operation

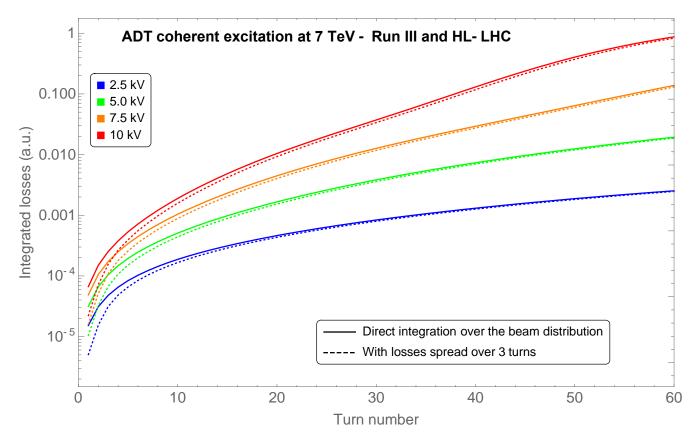


## A more refined model for the beam losses



## Integrated beam losses

- More realistic semi-analytical model to compute the losses: integration of the beam distribution with delayed losses spread over 3 turns (fractional part of the tune close to 1/3)
- Few differences except at the loss onset
- No conclusive difference observed for the main results as the loss thresholds are rigidly offset in time



- ➤ Integrated fractional beam losses as a function of the turn number for different ADT voltages.
- ➤ The two models are shown: direct integration over the beam distribution and integration with losses spread over 3 turns



## Losses and margins – Run III – 7.5 kV

 Margins are the same for the two models

